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### Understanding **Embedded - FPGAs (Field Programmable Gate Array)**

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

#### **Details**

Product Status	Active
Number of LABs/CLBs	25475
Number of Logic Elements/Cells	326080
Total RAM Bits	16404480
Number of I/O	500
Number of Gates	-
Voltage - Supply	0.97V ~ 1.03V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	900-BBGA, FCBGA
Supplier Device Package	900-FCBGA (31x31)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/xilinx/xc7k325t-1ff900c">https://www.e-xfl.com/product-detail/xilinx/xc7k325t-1ff900c</a>

Table 2: Recommended Operating Conditions (1) (Cont'd)

Symbol	Description	Min	Typ	Max	Units
$V_{MGTAVTTRCAL}$ (8)	Analog supply voltage for the resistor calibration circuit of the GTX transceiver column	1.17	1.2	1.23	V
<b>XADC</b>					
$V_{CCADC}$	XADC supply relative to GNDADC	1.71	1.80	1.89	V
$V_{REFP}$	Externally supplied reference voltage	1.20	1.25	1.30	V
<b>Temperature</b>					
$T_j$	Junction temperature operating range for commercial (C) temperature devices	0	–	85	°C
	Junction temperature operating range for extended (E) temperature devices	0	–	100	°C
	Junction temperature operating range for industrial (I) temperature devices	–40	–	100	°C

**Notes:**

1. All voltages are relative to ground.
2.  $V_{CCINT}$  and  $V_{CCBRAM}$  should be connected to the same supply.
3. Configuration data is retained even if  $V_{CCO}$  drops to 0V.
4. Includes  $V_{CCO}$  of 1.2V, 1.5V, 1.8V, 2.5V, and 3.3V.
5. The lower absolute voltage specification always applies.
6. A total of 200 mA per bank should not be exceeded.
7.  $V_{CCBATT}$  is required only when using bitstream encryption. If battery is not used, connect  $V_{CCBATT}$  to either ground or  $V_{CCAUX}$ .
8. Each voltage listed requires the filter circuit described in [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#).
9. For data rates  $\leq 10.3125$  Gb/s,  $V_{MGTAVCC}$  should be  $1.0V \pm 3\%$  for lower power consumption.
10. For lower power consumption,  $V_{MGTAVCC}$  should be  $1.0V \pm 3\%$  over the entire CPLL frequency range.

Table 3: DC Characteristics Over Recommended Operating Conditions

Symbol	Description	Min	Typ	Max	Units
$V_{DRINT}$	Data retention $V_{CCINT}$ voltage (below which configuration data might be lost)	0.75	–	–	V
$V_{DRI}$	Data retention $V_{CCAUX}$ voltage (below which configuration data might be lost)	1.5	–	–	V
$I_{REF}$	$V_{REF}$ leakage current per pin	–	–	15	μA
$I_L$	Input or output leakage current per pin (sample-tested)	–	–	15	μA
$C_{IN}$ (2)	Die input capacitance at the pad	–	–	8	pF
$I_{RPU}$	Pad pull-up (when selected) @ $V_{IN} = 0V$ , $V_{CCO} = 3.3V$	90	–	330	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$ , $V_{CCO} = 2.5V$	68	–	250	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$ , $V_{CCO} = 1.8V$	34	–	220	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$ , $V_{CCO} = 1.5V$	23	–	150	μA
	Pad pull-up (when selected) @ $V_{IN} = 0V$ , $V_{CCO} = 1.2V$	12	–	120	μA
$I_{RPD}$	Pad pull-down (when selected) @ $V_{IN} = 3.3V$	68	–	330	μA
	Pad pull-down (when selected) @ $V_{IN} = 1.8V$	45	–	180	μA
$I_{CCADC}$	Analog supply current, analog circuits in powered up state	–	–	25	mA
$I_{BATT}$ (3)	Battery supply current	–	–	150	nA

Table 5: Maximum Allowed AC Voltage Overshoot and Undershoot for 1.8V HP I/O Banks<sup>(1)(2)</sup> (Cont'd)

AC Voltage Overshoot	% of UI @-40°C to 100°C	AC Voltage Undershoot	% of UI @-40°C to 100°C
V <sub>CCO</sub> + 0.80	9.71	-0.80	50.0
V <sub>CCO</sub> + 0.85	4.51	-0.85	28.4
V <sub>CCO</sub> + 0.90	2.12	-0.90	12.7
V <sub>CCO</sub> + 0.95	1.01	-0.95	5.79

**Notes:**

1. A total of 200 mA per bank should not be exceeded.
2. For UI smaller than 20 µs.

Table 6: Typical Quiescent Supply Current

Symbol	Description	Device	Speed Grade				Units	
			1.0V		0.9V			
			-3	-2/-2L	-1	-2L		
I <sub>CCINTQ</sub>	Quiescent V <sub>CCINT</sub> supply current	XC7K70T	241	241	241	187	mA	
		XC7K160T	474	474	474	368	mA	
		XC7K325T	810	810	810	629	mA	
		XC7K355T	993	993	993	771	mA	
		XC7K410T	1080	1080	1080	838	mA	
		XC7K420T	1313	1313	1313	1019	mA	
		XC7K480T	1313	1313	1313	1019	mA	
I <sub>CCOQ</sub>	Quiescent V <sub>CCO</sub> supply current	XC7K70T	1	1	1	1	mA	
		XC7K160T	1	1	1	1	mA	
		XC7K325T	1	1	1	1	mA	
		XC7K355T	1	1	1	1	mA	
		XC7K410T	1	1	1	1	mA	
		XC7K420T	1	1	1	1	mA	
		XC7K480T	1	1	1	1	mA	
I <sub>CCAUXQ</sub>	Quiescent V <sub>CCAUX</sub> supply current	XC7K70T	21	21	21	21	mA	
		XC7K160T	40	40	40	40	mA	
		XC7K325T	68	68	68	68	mA	
		XC7K355T	75	75	75	75	mA	
		XC7K410T	85	85	85	85	mA	
		XC7K420T	99	99	99	99	mA	
		XC7K480T	99	99	99	99	mA	
I <sub>CCAUX_IOQ</sub>	Quiescent V <sub>CCAUX_IO</sub> supply current	XC7K70T	N/A	N/A	N/A	N/A	mA	
		XC7K160T	2	2	2	2	mA	
		XC7K325T	2	2	2	2	mA	
		XC7K355T	N/A	N/A	N/A	N/A	mA	
		XC7K410T	2	2	2	2	mA	
		XC7K420T	N/A	N/A	N/A	N/A	mA	
		XC7K480T	N/A	N/A	N/A	N/A	mA	

Table 6: Typical Quiescent Supply Current (Cont'd)

Symbol	Description	Device	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
I <sub>CCBRAMQ</sub>	Quiescent V <sub>CCBRAM</sub> supply current	XC7K70T	6	6	6	6	mA
		XC7K160T	14	14	14	14	mA
		XC7K325T	19	19	19	19	mA
		XC7K355T	31	31	31	31	mA
		XC7K410T	34	34	34	34	mA
		XC7K420T	41	41	41	41	mA
		XC7K480T	41	41	41	41	mA

**Notes:**

1. Typical values are specified at nominal voltage, 85°C junction temperatures ( $T_j$ ) with single-ended SelectIO resources.
2. Typical values are for blank configured devices with no output current loads, no active input pull-up resistors, all I/O pins are 3-state and floating.
3. Use the XPower™ Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate static power consumption for conditions other than those specified.

## Power-On/Off Power Supply Sequencing

The recommended power-on sequence is  $V_{CCINT}$ ,  $V_{CCBRAM}$ ,  $V_{CCAUX}$ ,  $V_{CCAUX\_IO}$ , and  $V_{CCO}$  to achieve minimum current draw and ensure that the I/Os are 3-stated at power-on. The recommended power-off sequence is the reverse of the power-on sequence. If  $V_{CCINT}$  and  $V_{CCBRAM}$  have the same recommended voltage levels then both can be powered by the same supply and ramped simultaneously. If  $V_{CCAUX}$ ,  $V_{CCAUX\_IO}$ , and  $V_{CCO}$  have the same recommended voltage levels then they can be powered by the same supply and ramped simultaneously.

For  $V_{CCO}$  voltages of 3.3V in HR I/O banks and configuration bank 0:

- The voltage difference between  $V_{CCO}$  and  $V_{CCAUX}$  must not exceed 2.625V for longer than  $T_{VCCO2VCCAUX}$  for each power-on/off cycle to maintain device reliability levels.
- The  $T_{VCCO2VCCAUX}$  time can be allocated in any percentage between the power-on and power-off ramps.

The recommended power-on sequence to achieve minimum current draw for the GTX transceivers is  $V_{CCINT}$ ,  $V_{MGTAVCC}$ ,  $V_{MGTAVTT}$  OR  $V_{MGTAVCC}$ ,  $V_{CCINT}$ ,  $V_{MGTAVTT}$ . There is no recommended sequencing for  $V_{MGTAVCCAUX}$ . Both  $V_{MGTAVCC}$  and  $V_{CCINT}$  can be ramped simultaneously. The recommended power-off sequence is the reverse of the power-on sequence to achieve minimum current draw.

If these recommended sequences are not met, current drawn from  $V_{MGTAVTT}$  can be higher than specifications during power-up and power-down.

- When  $V_{MGTAVTT}$  is powered before  $V_{MGTAVCC}$  and  $V_{MGTAVTT} - V_{MGTAVCC} > 150$  mV and  $V_{MGTAVCC} < 0.7V$ , the  $V_{MGTAVTT}$  current draw can increase by 460 mA per transceiver during  $V_{MGTAVCC}$  ramp up. The duration of the current draw can be up to  $0.3 \times T_{MGTAVCC}$  (ramp time from GND to 90% of  $V_{MGTAVCC}$ ). The reverse is true for power-down.
- When  $V_{MGTAVTT}$  is powered before  $V_{CCINT}$  and  $V_{MGTAVTT} - V_{CCINT} > 150$  mV and  $V_{CCINT} < 0.7V$ , the  $V_{MGTAVTT}$  current draw can increase by 50 mA per transceiver during  $V_{CCINT}$  ramp up. The duration of the current draw can be up to  $0.3 \times T_{VCCINT}$  (ramp time from GND to 90% of  $V_{CCINT}$ ). The reverse is true for power-down.

**Table 7** shows the minimum current, in addition to  $I_{CCQ}$ , that are required by Kintex-7 devices for proper power-on and configuration. If the current minimums shown in **Table 6** and **Table 7** are met, the device powers on after all five supplies have passed through their power-on reset threshold voltages. The FPGA must not be configured until after  $V_{CCINT}$  is applied.

Once initialized and configured, use the XPower tools to estimate current drain on these supplies.

**Table 7: Power-On Current for Kintex-7 Devices**

Device	$I_{CCINTMIN}$	$I_{CCAUXMIN}$	$I_{CCOMIN}$	$I_{CCAUX\_IOMIN}$	$I_{CCBRAMMIN}$	Units
	Typ <sup>(1)</sup>	Typ <sup>(1)</sup>	Typ <sup>(1)</sup>	Typ <sup>(1)</sup>	Typ <sup>(1)</sup>	
XC7K70T	$I_{CCINTQ} + 450$	$I_{CCAUXQ} + 40$	$I_{CCOQ} + 40 \text{ mA per bank}$	$I_{CCOAUXIOQ} + 40 \text{ mA per bank}$	$I_{CCBRAMQ} + 40$	mA
XC7K160T	$I_{CCINTQ} + 550$	$I_{CCAUXQ} + 50$	$I_{CCOQ} + 40 \text{ mA per bank}$	$I_{CCOAUXIOQ} + 40 \text{ mA per bank}$	$I_{CCBRAMQ} + 40$	mA
XC7K325T	$I_{CCINTQ} + 600$	$I_{CCAUXQ} + 80$	$I_{CCOQ} + 40 \text{ mA per bank}$	$I_{CCOAUXIOQ} + 40 \text{ mA per bank}$	$I_{CCBRAMQ} + 40$	mA
XC7K355T	$I_{CCINTQ} + 1450$	$I_{CCAUXQ} + 109$	$I_{CCOQ} + 40 \text{ mA per bank}$	$I_{CCOAUXIOQ} + 40 \text{ mA per bank}$	$I_{CCBRAMQ} + 81$	mA
XC7K410T	$I_{CCINTQ} + 1500$	$I_{CCAUXQ} + 125$	$I_{CCOQ} + 40 \text{ mA per bank}$	$I_{CCOAUXIOQ} + 40 \text{ mA per bank}$	$I_{CCBRAMQ} + 90$	mA
XC7K420T	$I_{CCINTQ} + 2200$	$I_{CCAUXQ} + 180$	$I_{CCOQ} + 40 \text{ mA per bank}$	$I_{CCOAUXIOQ} + 40 \text{ mA per bank}$	$I_{CCBRAMQ} + 108$	mA
XC7K480T	$I_{CCINTQ} + 2200$	$I_{CCAUXQ} + 180$	$I_{CCOQ} + 40 \text{ mA per bank}$	$I_{CCOAUXIOQ} + 40 \text{ mA per bank}$	$I_{CCBRAMQ} + 108$	mA

**Notes:**

1. Typical values are specified at nominal voltage, 25°C.
2. Use the XPower Estimator (XPE) spreadsheet tool (download at <http://www.xilinx.com/power>) to calculate maximum power-on currents.

**Table 8: Power Supply Ramp Time**

Symbol	Description	Conditions	Min	Max	Units
$T_{VCCINT}$	Ramp time from GND to 90% of $V_{CCINT}$		0.2	50	ms
$T_{VCCO}$	Ramp time from GND to 90% of $V_{CCO}$		0.2	50	ms
$T_{VCCAUX}$	Ramp time from GND to 90% of $V_{CCAUX}$		0.2	50	ms
$T_{VCCAUX\_IO}$	Ramp time from GND to 90% of $V_{CCAUX\_IO}$		0.2	50	ms
$T_{CCBRAM}$	Ramp time from GND to 90% of $V_{CCBRAM}$		0.2	50	ms
$T_{VCCO2VCCAUX}$	Allowed time per power cycle for $V_{CCO} - V_{CCAUX} > 2.625\text{V}$	$T_J = 100^\circ\text{C}^{(1)}$	–	500	ms
		$T_J = 85^\circ\text{C}^{(1)}$	–	800	
$T_{MGTAVCC}$	Ramp time from GND to 90% of $V_{MGTAVCC}$		0.2	50	ms
$T_{MGTAVTT}$	Ramp time from GND to 90% of $V_{MGTAVTT}$		0.2	50	ms
$T_{MGTVCCAUX}$	Ramp time from GND to 90% of $V_{MGTVCCAUX}$		0.2	50	ms

**Notes:**

1. Based on 240,000 power cycles with nominal  $V_{CCO}$  of 3.3V or 36,500 power cycles with a worst case  $V_{CCO}$  of 3.465V.

Table 17: Maximum Physical Interface (PHY) Rate for Memory Interfaces (FFG Packages)<sup>(1)(2)</sup>

Memory Standard	I/O Bank Type	V <sub>CCAUX_IO</sub>	Speed Grade				Units
			1.0V			0.9V	
			-3	-2/-2L	-1	-2L	
<b>4:1 Memory Controllers</b>							
DDR3	HP	2.0V	1866	1866	1600	1333	Mb/s
	HP	1.8V	1600	1333	1066	1066	Mb/s
	HR	N/A	1066	1066	800	800	Mb/s
DDR3L	HP	2.0V	1600	1600	1333	1066	Mb/s
	HP	1.8V	1333	1066	800	800	Mb/s
	HR	N/A	800	800	667	667	Mb/s
DDR2	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V	800	800	800	800	Mb/s
	HR	N/A	800	800	800	800	Mb/s
RLDRAM III <sup>(3)</sup>	HP	2.0V	800	667	667	533	MHz
	HP	1.8V	550	500	450	450	MHz
	HR	N/A			N/A		
<b>2:1 Memory Controllers</b>							
DDR3	HP	2.0V	1066	1066	800	800	Mb/s
	HP	1.8V	1066	1066	800	800	Mb/s
	HR	N/A	1066	1066	800	800	Mb/s
DDR3L	HP	2.0V	1066	1066	800	800	Mb/s
	HP	1.8V	1066	1066	800	800	Mb/s
	HR	N/A	800	800	667	667	Mb/s
DDR2	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V					
	HR	N/A					
QDR II+ <sup>(4)</sup>	HP	2.0V	550	500	450	450	MHz
	HP	1.8V					
	HR	N/A					
RLDRAM II	HP	2.0V	533	500	450	450	MHz
	HP	1.8V					
	HR	N/A					
LPDDR2 <sup>(3)</sup>	HP	2.0V	800	800	800	800	Mb/s
	HP	1.8V	800	800	800	800	Mb/s
	HR	N/A	800	667	667	667	Mb/s

**Notes:**

1. V<sub>REF</sub> tracking is required. For more information, see [UG586, 7 Series FPGAs Memory Interface Solutions User Guide](#).
2. When using the internal V<sub>REF</sub> the maximum data rate is 800 Mb/s (400 MHz).
3. RLDRAM III (BL = 4, BL = 8) and LPDDR2 specifications have not been validated with memory IP.
4. The maximum QDRII+ performance specifications are for burst-length 4 (BL = 4) implementations. Burst length 2 (BL = 2) implementations are limited to 333 MHz for all speed grades and I/O bank types.

## IOB Pad Input/Output/3-State

**Table 19** (3.3V high-range IOB (HR)) and **Table 20** (1.8V high-performance IOB (HP)) summarizes the values of standard-specific data input delay adjustments, output delays terminating at pads (based on standard) and 3-state delays.

- $T_{IOP}$  is described as the delay from IOB pad through the input buffer to the I-pin of an IOB pad. The delay varies depending on the capability of the SelectIO input buffer.
- $T_{IOOP}$  is described as the delay from the O pin to the IOB pad through the output buffer of an IOB pad. The delay varies depending on the capability of the SelectIO output buffer.
- $T_{IOTP}$  is described as the delay from the T pin to the IOB pad through the output buffer of an IOB pad, when 3-state is disabled. The delay varies depending on the SelectIO capability of the output buffer. In HP I/O banks, the internal DCI termination turn-on time is always faster than  $T_{IOTP}$  when the DCITERMDISABLE pin is used. In HR I/O banks, the IN\_TERM termination turn-on time is always faster than  $T_{IOTP}$  when the INTERMDISABLE pin is used.

Table 19: 3.3V IOB High Range (HR) Switching Characteristics

I/O Standard	$T_{IOP}$			$T_{IOOP}$			$T_{IOTP}$			Units		
	Speed Grade			Speed Grade			Speed Grade					
	1.0V		0.9V	1.0V		0.9V	1.0V		0.9V			
	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L	-3	-2/-2L	-1	-2L
LVTTL_S4	1.31	1.42	1.64	1.51	5.27	5.63	6.05	4.13	6.03	6.49	7.04	4.64 ns
LVTTL_S8	1.31	1.42	1.64	1.51	4.45	4.83	5.30	3.86	5.21	5.69	6.29	4.38 ns
LVTTL_S12	1.31	1.42	1.64	1.51	4.45	4.83	5.29	3.84	5.21	5.69	6.28	4.36 ns
LVTTL_S16	1.31	1.42	1.64	1.51	3.47	3.88	4.40	3.39	4.23	4.74	5.39	3.91 ns
LVTTL_S24	1.31	1.42	1.64	1.51	3.58	3.99	4.51	3.61	4.34	4.85	5.50	4.13 ns
LVTTL_F4	1.31	1.42	1.64	1.51	4.70	4.98	5.29	3.58	5.46	5.84	6.28	4.09 ns
LVTTL_F8	1.31	1.42	1.64	1.51	3.66	4.06	4.56	3.06	4.42	4.92	5.55	3.58 ns
LVTTL_F12	1.31	1.42	1.64	1.51	3.66	4.06	4.56	3.05	4.42	4.92	5.55	3.56 ns
LVTTL_F16	1.31	1.42	1.64	1.51	2.57	2.85	3.15	2.88	3.33	3.71	4.14	3.39 ns
LVTTL_F24	1.31	1.42	1.64	1.51	2.41	2.64	2.89	2.94	3.17	3.50	3.88	3.45 ns
LVDS_25 <sup>(1)</sup>	0.64	0.68	0.80	0.83	1.36	1.47	1.55	1.58	2.12	2.33	2.54	2.09 ns
MINI_LVDS_25	0.68	0.70	0.79	0.83	1.36	1.47	1.55	1.59	2.12	2.33	2.54	2.11 ns
BLVDS_25 <sup>(1)</sup>	0.65	0.69	0.80	0.83	1.83	2.02	2.20	2.16	2.59	2.88	3.19	2.67 ns
RSDS_25 (point to point) <sup>(1)</sup>	0.63	0.68	0.79	0.83	1.36	1.48	1.55	1.59	2.12	2.34	2.54	2.11 ns
PPDS_25 <sup>(1)</sup>	0.65	0.69	0.80	0.83	1.36	1.49	1.58	1.59	2.12	2.35	2.57	2.11 ns
TMDS_33 <sup>(1)</sup>	0.72	0.76	0.86	0.83	1.43	1.54	1.60	1.70	2.19	2.40	2.59	2.22 ns
PCI33_3 <sup>(1)</sup>	1.28	1.41	1.65	1.50	2.71	3.08	3.52	3.42	3.47	3.94	4.51	3.94 ns
HSUL_12	0.63	0.64	0.71	0.79	2.06	2.31	2.59	2.13	2.82	3.17	3.58	2.64 ns
DIFF_HSUL_12	0.58	0.61	0.70	0.81	1.83	2.04	2.26	1.92	2.59	2.90	3.25	2.44 ns
HSTL_I_S	0.61	0.64	0.73	0.79	1.55	1.69	1.80	1.91	2.31	2.55	2.79	2.42 ns
HSTL_II_S	0.61	0.64	0.73	0.78	1.21	1.34	1.43	1.70	1.97	2.20	2.42	2.22 ns
HSTL_I_18_S	0.64	0.67	0.76	0.79	1.28	1.39	1.45	1.58	2.04	2.25	2.44	2.09 ns
HSTL_II_18_S	0.64	0.67	0.76	0.79	1.18	1.31	1.40	1.69	1.94	2.17	2.39	2.20 ns
DIFF_HSTL_I_S	0.63	0.67	0.77	0.78	1.42	1.54	1.61	1.84	2.18	2.40	2.60	2.36 ns
DIFF_HSTL_II_S	0.63	0.67	0.77	0.79	1.15	1.24	1.27	1.78	1.91	2.10	2.26	2.30 ns
DIFF_HSTL_I_18_S	0.65	0.69	0.78	0.79	1.27	1.38	1.43	1.67	2.03	2.24	2.42	2.19 ns
DIFF_HSTL_II_18_S	0.65	0.69	0.78	0.81	1.14	1.23	1.26	1.72	1.90	2.09	2.25	2.23 ns

Table 23: OLOGIC Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
<b>Setup/Hold</b>						
TODCK/TOCKD	D1/D2 pins Setup/Hold with respect to CLK	0.45/-0.13	0.50/-0.13	0.58/-0.13	0.79/-0.18	ns
TOOCECK/TOCKOCE	OCE pin Setup/Hold with respect to CLK	0.28/0.03	0.29/0.03	0.45/0.03	0.35/-0.10	ns
TOSRCK/TOCKSR	SR pin Setup/Hold with respect to CLK	0.32/0.18	0.38/0.18	0.70/0.18	0.62/-0.04	ns
TOTCK/TOCKT	T1/T2 pins Setup/Hold with respect to CLK	0.49/-0.16	0.56/-0.16	0.68/-0.16	0.67/-0.18	ns
TOTCECK/TOCKTCE	TCE pin Setup/Hold with respect to CLK	0.28/0.01	0.30/0.01	0.45/0.01	0.31/-0.10	ns
<b>Combinatorial</b>						
TODQ	D1 to OQ out or T1 to TQ out	0.73	0.81	0.97	1.18	ns
<b>Sequential Delays</b>						
TOCKQ	CLK to OQ/TQ out	0.41	0.43	0.49	0.63	ns
TRQ_OLOGICE2	SR pin to OQ/TQ out (HP I/O banks only)	0.63	0.70	0.83	1.12	ns
TGSRQ_OLOGICE2	Global Set/Reset to Q outputs (HP I/O banks only)	7.60	7.60	10.51	11.39	ns
TRQ_OLOGICE3	SR pin to OQ/TQ out (HR I/O banks only)	0.63	0.70	0.83	1.12	ns
TGSRQ_OLOGICE3	Global Set/Reset to Q outputs (HR I/O banks only)	7.60	7.60	10.51	11.39	ns
<b>Set/Reset</b>						
TRPW_OLOGICE2	Minimum Pulse Width, SR inputs (HP I/O banks only)	0.54	0.54	0.63	0.68	ns, Min
TRPW_OLOGICE3	Minimum Pulse Width, SR inputs (HR I/O banks only)	0.54	0.54	0.63	0.68	ns, Min

## Input/Output Delay Switching Characteristics

Table 26: Input/Output Delay Switching Characteristics

Symbol	Description	Speed Grade				Units	
		1.0V		0.9V			
		-3	-2/-2L	-1	-2L		
<b>IDELAYCTRL</b>							
T <sub>DLYCCO_RDY</sub>	Reset to Ready for IDELAYCTRL	3.22	3.22	3.22	3.22	μs	
F <sub>IDELAYCTRL_REF</sub>	Attribute REFCLK frequency = 200.00 <sup>(1)</sup>	200.00	200.00	200.00	200.00	MHz	
	Attribute REFCLK frequency = 300.00 <sup>(1)</sup>	300.00	300.00	N/A	N/A	MHz	
IDELAYCTRL_REF_PRECISION	REFCLK precision	±10	±10	±10	±10	MHz	
T <sub>IDELAYCTRL_RPW</sub>	Minimum Reset pulse width	52.00	52.00	52.00	52.00	ns	
<b>IDELAY/ODELAY</b>							
T <sub>IDELAYRESOLUTION</sub>	IDELAY/ODELAY chain delay resolution	1/(32 x 2 x F <sub>REF</sub> )				ps	
T <sub>IDELAYPAT_JIT</sub> and T <sub>ODELAYPAT_JIT</sub>	Pattern dependent period jitter in delay chain for clock pattern. <sup>(2)</sup>	0	0	0	0	ps per tap	
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23) <sup>(3)</sup>	±5	±5	±5	±5	ps per tap	
	Pattern dependent period jitter in delay chain for random data pattern (PRBS 23) <sup>(4)</sup>	±9	±9	±9	±9	ps per tap	
T <sub>IDELAY_CLK_MAX</sub> /T <sub>ODELAY_CLK_MAX</sub>	Maximum frequency of CLK input to IDELAY/ODELAY	800.00	800.00	710.00	710.00	MHz	
T <sub>IDCCK_CE</sub> / T <sub>IDCKC_CE</sub>	CE pin Setup/Hold with respect to C for IDELAY	0.11/0.10	0.14/0.12	0.18/0.14	0.14/0.16	ns	
T <sub>ODCCK_CE</sub> / T <sub>ODCKC_CE</sub>	CE pin Setup/Hold with respect to C for ODELAY	0.14/0.03	0.16/0.04	0.19/0.05	0.28/0.06	ns	
T <sub>IDCCK_INC</sub> / T <sub>IDCKC_INC</sub>	INC pin Setup/Hold with respect to C for IDELAY	0.10/0.14	0.12/0.16	0.14/0.20	0.10/0.23	ns	
T <sub>ODCCK_INC</sub> / T <sub>ODCKC_INC</sub>	INC pin Setup/Hold with respect to C for ODELAY	0.10/0.07	0.12/0.08	0.13/0.09	0.19/0.16	ns	
T <sub>IDCCK_RST</sub> / T <sub>IDCKC_RST</sub>	RST pin Setup/Hold with respect to C for IDELAY	0.13/0.08	0.14/0.10	0.16/0.12	0.22/0.19	ns	
T <sub>ODCCK_RST</sub> / T <sub>ODCKC_RST</sub>	RST pin Setup/Hold with respect to C for ODELAY	0.16/0.04	0.19/0.06	0.24/0.08	0.32/0.11	ns	
T <sub>IDDO_IDATAIN</sub>	Propagation delay through IDELAY	Note 5	Note 5	Note 5	Note 5	ps	
T <sub>ODDO_ODATAIN</sub>	Propagation delay through ODELAY	Note 5	Note 5	Note 5	Note 5	ps	

**Notes:**

1. Average Tap Delay at 200 MHz = 78 ps, at 300 MHz = 52 ps.
2. When HIGH\_PERFORMANCE mode is set to TRUE or FALSE.
3. When HIGH\_PERFORMANCE mode is set to TRUE.
4. When HIGH\_PERFORMANCE mode is set to FALSE.
5. Delay depends on IDELAY/ODELAY tap setting. See TRACE report for actual values.

Table 27: IO\_FIFO Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
<b>IO_FIFO Clock to Out Delays</b>						
T <sub>OFFCKO_DO</sub>	RDCLK to Q outputs	0.51	0.56	0.63	0.81	ns
T <sub>CKO_FLAGS</sub>	Clock to IO_FIFO Flags	0.59	0.62	0.81	0.77	ns
<b>Setup/Hold</b>						
T <sub>CCK_D/T<sub>CKC_D</sub></sub>	D inputs to WRCLK	0.43/-0.01	0.47/-0.01	0.53/-0.01	0.76/-0.05	ns
T <sub>IFFCCK_WREN/T<sub>IFFCKC_WREN</sub></sub>	WREN to WRCLK	0.39/-0.01	0.43/-0.01	0.50/-0.01	0.70/-0.05	ns
T <sub>OFFCCK_RDEN/T<sub>OFFCKC_RDEN</sub></sub>	RDEN to RDCLK	0.49/0.01	0.53/0.02	0.61/0.02	0.79/-0.02	ns
<b>Minimum Pulse Width</b>						
T <sub>PWH_IO_FIFO</sub>	RESET, RDCLK, WRCLK	0.81	0.92	1.08	1.29	ns
T <sub>PWL_IO_FIFO</sub>	RESET, RDCLK, WRCLK	0.81	0.92	1.08	1.29	ns
<b>Maximum Frequency</b>						
F <sub>MAX</sub>	RDCLK and WRCLK	533.05	470.37	400.00	333.33	MHz

**CLB Distributed RAM Switching Characteristics (SLICEM Only)****Table 29: CLB Distributed RAM Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
<b>Sequential Delays</b>						
T <sub>SHCKO</sub>	Clock to A – B outputs	0.68	0.70	0.85	1.08	ns, Max
T <sub>SHCKO_1</sub>	Clock to AMUX – BMUX outputs	0.91	0.95	1.15	1.44	ns, Max
<b>Setup and Hold Times Before/After Clock CLK</b>						
T <sub>DS_LRAM</sub> /T <sub>DH_LRAM</sub>	A – D inputs to CLK	0.45/0.23	0.45/0.24	0.54/0.27	0.69/0.33	ns, Min
T <sub>AS_LRAM</sub> /T <sub>AH_LRAM</sub>	Address An inputs to clock	0.13/0.50	0.14/0.50	0.17/0.58	0.21/0.63	ns, Min
	Address An inputs through MUXs and/or carry logic to clock	0.40/0.16	0.42/0.17	0.52/0.23	0.63/0.23	ns, Min
T <sub>WS_LRAM</sub> /T <sub>WH_LRAM</sub>	WE input to clock	0.29/0.09	0.30/0.09	0.36/0.09	0.46/0.10	ns, Min
T <sub>CECK_LRAM</sub> / T <sub>CKCE_LRAM</sub>	CE input to CLK	0.29/0.09	0.30/0.09	0.37/0.09	0.47/0.10	ns, Min
<b>Clock CLK</b>						
T <sub>MPW</sub>	Minimum pulse width	0.68	0.77	0.91	1.11	ns, Min
T <sub>MCP</sub>	Minimum clock period	1.35	1.54	1.82	2.22	ns, Min

**Notes:**

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.
2. T<sub>SHCKO</sub> also represents the CLK to XMUX output. Refer to TRACE report for the CLK to XMUX path.

**CLB Shift Register Switching Characteristics (SLICEM Only)****Table 30: CLB Shift Register Switching Characteristics**

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
<b>Sequential Delays</b>						
T <sub>REG</sub>	Clock to A – D outputs	0.96	0.98	1.20	1.35	ns, Max
T <sub>REG_MUX</sub>	Clock to AMUX – DMUX output	1.19	1.23	1.50	1.72	ns, Max
T <sub>REG_M31</sub>	Clock to DMUX output via M31 output	0.89	0.91	1.10	1.25	ns, Max
<b>Setup and Hold Times Before/After Clock CLK</b>						
T <sub>WS_SHFREG</sub> / T <sub>WH_SHFREG</sub>	WE input	0.26/0.09	0.27/0.09	0.33/0.09	0.41/0.10	ns, Min
T <sub>CECK_SHFREG</sub> / T <sub>CKCE_SHFREG</sub>	CE input to CLK	0.27/0.09	0.28/0.09	0.33/0.09	0.42/0.10	ns, Min
T <sub>DS_SHFREG</sub> / T <sub>DH_SHFREG</sub>	A – D inputs to CLK	0.28/0.26	0.28/0.26	0.33/0.30	0.41/0.36	ns, Min
<b>Clock CLK</b>						
T <sub>MPW_SHFREG</sub>	Minimum pulse width	0.55	0.65	0.78	0.91	ns, Min

**Notes:**

1. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.

## DSP48E1 Switching Characteristics

Table 32: DSP48E1 Switching Characteristics

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
<b>Setup and Hold Times of Data/Control Pins to the Input Register Clock</b>						
T <sub>DSPDCK_A_AREG</sub> /T <sub>DSPCKD_A_AREG</sub>	A input to A register CLK	0.24/ 0.12	0.27/ 0.14	0.31/ 0.16	0.38/ 0.12	ns
T <sub>DSPDCK_B_BREG</sub> /T <sub>DSPCKD_B_BREG</sub>	B input to B register CLK	0.28/ 0.13	0.32/ 0.14	0.39/ 0.15	0.51/ 0.16	ns
T <sub>DSPDCK_C_CREG</sub> /T <sub>DSPCKD_C_CREG</sub>	C input to C register CLK	0.15/ 0.15	0.17/ 0.17	0.20/ 0.20	0.31/ 0.21	ns
T <sub>DSPDCK_D_DREG</sub> /T <sub>DSPCKD_D_DREG</sub>	D input to D register CLK	0.21/ 0.19	0.27/ 0.22	0.35/ 0.26	0.46/ 0.20	ns
T <sub>DSPDCK_ACIN_AREG</sub> /T <sub>DSPCKD_ACIN_AREG</sub>	ACIN input to A register CLK	0.21/ 0.12	0.24/ 0.14	0.27/ 0.16	0.31/ 0.12	ns
T <sub>DSPDCK_BCIN_BREG</sub> /T <sub>DSPCKD_BCIN_BREG</sub>	BCIN input to B register CLK	0.22/ 0.13	0.25/ 0.14	0.30/ 0.15	0.34/ 0.16	ns
<b>Setup and Hold Times of Data Pins to the Pipeline Register Clock</b>						
T <sub>DSPDCK_{A,B}_MREG_MULT</sub> / T <sub>DSPCKD_B_MREG_MULT</sub>	{A, B} input to M register CLK using multiplier	2.04/ -0.01	2.34/ -0.01	2.79/ -0.01	3.66/ -0.06	ns
T <sub>DSPDCK_{A,B}_ADREG</sub> /T <sub>DSPCKD_D_ADREG</sub>	{A, D} input to AD register CLK	1.09/ -0.02	1.25/ -0.02	1.49/ -0.02	1.94/ -0.23	ns
<b>Setup and Hold Times of Data/Control Pins to the Output Register Clock</b>						
T <sub>DSPDCK_{A,B}_PREG_MULT</sub> / T <sub>DSPCKD_{A,B}_PREG_MULT</sub>	{A, B} input to P register CLK using multiplier	3.41/ -0.24	3.90/ -0.24	4.64/ -0.24	5.89/ -0.41	ns
T <sub>DSPDCK_D_PREG_MULT</sub> / T <sub>DSPCKD_D_PREG_MULT</sub>	D input to P register CLK using multiplier	3.33/ -0.62	3.81/ -0.62	4.53/ -0.62	5.70/ -1.42	ns
T <sub>DSPDCK_{A,B}_PREG</sub> / T <sub>DSPCKD_{A,B}_PREG</sub>	A or B input to P register CLK not using multiplier	1.47/ -0.24	1.68/ -0.24	2.00/ -0.24	2.37/ -0.41	ns
T <sub>DSPDCK_C_PREG</sub> /T <sub>DSPCKD_C_PREG</sub>	C input to P register CLK not using multiplier	1.30/ -0.22	1.49/ -0.22	1.78/ -0.22	2.11/ -0.36	ns
T <sub>DSPDCK_PCIN_PREG</sub> /T <sub>DSPCKD_PCIN_PREG</sub>	PCIN input to P register CLK	1.12/ -0.13	1.28/ -0.13	1.52/ -0.13	1.81/ -0.21	ns
<b>Setup and Hold Times of the CE Pins</b>						
T <sub>DSPDCK_{CEA;CEB}_{AREG;BREG}</sub> / T <sub>DSPCKD_{CEA;CEB}_{AREG;BREG}</sub>	{CEA; CEB} input to {A; B} register CLK	0.30/ 0.05	0.36/ 0.06	0.44/ 0.09	0.55/ 0.09	ns
T <sub>DSPDCK_CEC_CREG</sub> /T <sub>DSPCKD_CEC_CREG</sub>	CEC input to C register CLK	0.24/ 0.08	0.29/ 0.09	0.36/ 0.11	0.43/ 0.11	ns
T <sub>DSPDCK_CED_DREG</sub> /T <sub>DSPCKD_CED_DREG</sub>	CED input to D register CLK	0.31/ -0.02	0.36/ -0.02	0.44/ -0.02	0.58/ 0.12	ns
T <sub>DSPDCK_CEM_MREG</sub> /T <sub>DSPCKD_CEM_MREG</sub>	CEM input to M register CLK	0.26/ 0.15	0.29/ 0.17	0.33/ 0.20	0.39/ 0.25	ns
T <sub>DSPDCK_CEP_PREG</sub> /T <sub>DSPCKD_CEP_PREG</sub>	CEP input to P register CLK	0.31/ 0.01	0.36/ 0.01	0.45/ 0.01	0.54/ 0.00	ns

## Clock Buffers and Networks

Table 33: Global Clock Switching Characteristics (Including BUFGCTRL)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T_BCCCK_CE/T_BCCKC_CE <sup>(1)</sup>	CE pins Setup/Hold	0.12/0.30	0.14/0.38	0.26/0.38	0.23/0.40	ns
T_BCCCK_S/T_BCCKC_S <sup>(1)</sup>	S pins Setup/Hold	0.12/0.30	0.14/0.38	0.26/0.38	0.23/0.40	ns
T_BGCKO_O <sup>(2)</sup>	BUFGCTRL delay from I0/I1 to O	0.08	0.10	0.12	0.10	ns
<b>Maximum Frequency</b>						
F <sub>MAX_BUFG</sub>	Global clock tree (BUFG)	741.00	710.00	625.00	560.00	MHz

**Notes:**

1. T<sub>BCCCK\_CE</sub> and T<sub>BCCKC\_CE</sub> must be satisfied to assure glitch-free operation of the global clock when switching between clocks. These parameters do not apply to the BUFGMUX primitive that assures glitch-free operation. The other global clock setup and hold times are optional; only needing to be satisfied if device operation requires simulation matches on a cycle-for-cycle basis when switching between clocks.
2. T<sub>BGCKO\_O</sub> (BUFG delay from I0 to O) values are the same as T<sub>BCCKO\_O</sub> values.

Table 34: Input/Output Clock Switching Characteristics (BUFIO)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T_BLOCKO_O	Clock to out delay from I to O	1.04	1.14	1.32	1.48	ns
<b>Maximum Frequency</b>						
F <sub>MAX_BUFIO</sub>	I/O clock tree (BUFIO)	800.00	800.00	710.00	710.00	MHz

Table 35: Regional Clock Buffer Switching Characteristics (BUFR)

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
T_BRCKO_O	Clock to out delay from I to O	0.60	0.65	0.77	1.06	ns
T_BRCKO_O_BYP	Clock to out delay from I to O with Divide Bypass attribute set	0.30	0.32	0.38	0.57	ns
T_BRDO_O	Propagation delay from CLR to O	0.71	0.75	0.96	0.93	ns
<b>Maximum Frequency</b>						
F <sub>MAX_BUFR</sub> <sup>(1)</sup>	Regional clock tree (BUFR)	600.00	540.00	450.00	450.00	MHz

**Notes:**

1. The maximum input frequency to the BUFR is the BUFIO F<sub>MAX</sub> frequency.

**Table 42: Clock-Capable Clock Input to Output Delay With MMCM**

Symbol	Description	Device	Speed Grade				Units
			1.0V		0.9V		
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with MMCM</i> .							
TICKOFMMCMCC	Clock-capable clock input and OUTFF <i>with MMCM</i>	XC7K70T	0.95	0.95	0.95	1.74	ns
		XC7K160T	0.96	0.96	0.96	1.78	ns
		XC7K325T	1.00	1.00	1.00	1.82	ns
		XC7K355T	1.00	1.00	1.00	1.78	ns
		XC7K410T	1.00	1.00	1.00	1.82	ns
		XC7K420T	1.07	1.07	1.07	1.82	ns
		XC7K480T	1.07	1.07	1.07	1.82	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. MMCM output jitter is already included in the timing calculation.

**Table 43: Clock-Capable Clock Input to Output Delay With PLL**

Symbol	Description	Device	Speed Grade				Units
			1.0V		0.9V		
			-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with PLL</i> .							
TICKOFPLLCC	Clock-capable clock input and OUTFF <i>with PLL</i>	XC7K70T	0.84	0.84	0.84	1.45	ns
		XC7K160T	0.89	0.89	0.89	1.54	ns
		XC7K325T	0.89	0.89	0.89	1.54	ns
		XC7K355T	0.89	0.89	0.89	1.50	ns
		XC7K410T	0.89	0.89	0.89	1.54	ns
		XC7K420T	0.96	0.96	0.96	1.54	ns
		XC7K480T	0.96	0.96	0.96	1.54	ns

**Notes:**

1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. PLL output jitter is already included in the timing calculation.

**Table 44: Pin-to-Pin, Clock-to-Out using BUFI0**

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
SSTL15 Clock-Capable Clock Input to Output Delay using Output Flip-Flop, Fast Slew Rate, <i>with BUFI0</i> .						
TICKOFC0	Clock-to-Out of I/O clock for HR I/O banks	4.93	5.52	6.20	6.97	ns
	Clock-to-Out of I/O clock for HP I/O banks	4.85	5.44	6.11	6.90	ns

## Device Pin-to-Pin Input Parameter Guidelines

All devices are 100% functionally tested. Values are expressed in nanoseconds unless otherwise noted.

**Table 45: Global Clock Input Setup and Hold Without MMCM/PLL with ZHOLD\_DELAY on HR I/O Banks**

Symbol	Description	Device	Speed Grade				Units	
			1.0V		0.9V			
			-3	-2/-2L	-1	-2L		
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. <sup>(1)</sup>								
$T_{PSFD}/T_{PHFD}$	Full Delay (Legacy Delay or Default Delay) Global Clock Input and IFF <sup>(2)</sup> without MMCM/PLL with ZHOLD_DELAY on HR I/O Banks	XC7K70T	2.83/-0.29	2.95/-0.29	3.15/-0.29	4.96/-0.33	ns	
		XC7K160T	3.17/-0.35	3.29/-0.35	3.55/-0.35	5.54/-0.49	ns	
		XC7K325T	2.83/-0.06	2.94/-0.06	3.15/-0.06	5.18/-0.14	ns	
		XC7K355T	3.26/-0.32	3.41/-0.32	3.67/-0.32	5.84/-0.49	ns	
		XC7K410T	3.43/-0.34	3.59/-0.34	3.88/-0.34	6.21/-0.54	ns	
		XC7K420T	3.37/-0.27	3.48/-0.27	3.76/-0.27	6.00/-0.52	ns	
		XC7K480T	3.37/-0.27	3.48/-0.27	3.76/-0.27	6.00/-0.52	ns	

### Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. A Zero "0" Hold Time listing indicates no hold time or a negative hold time.

**Table 46: Clock-Capable Clock Input Setup and Hold With MMCM**

Symbol	Description	Device	Speed Grade				Units	
			1.0V		0.9V			
			-3	-2/-2L	-1	-2L		
Input Setup and Hold Time Relative to Global Clock Input Signal for SSTL15 Standard. <sup>(1)</sup>								
$T_{PSMMCMCC}/T_{PHMMCMCC}$	No Delay clock-capable clock input and IFF <sup>(2)</sup> with MMCM	XC7K70T	2.39/-0.22	2.65/-0.22	2.94/-0.22	2.21/-0.44	ns	
		XC7K160T	2.49/-0.20	2.77/-0.20	3.07/-0.20	2.38/-0.47	ns	
		XC7K325T	2.55/-0.16	2.85/-0.16	3.14/-0.16	2.60/-0.47	ns	
		XC7K355T	2.43/-0.16	2.73/-0.16	3.00/-0.16	2.47/-0.43	ns	
		XC7K410T	2.55/-0.16	2.84/-0.16	3.14/-0.16	2.58/-0.47	ns	
		XC7K420T	2.47/-0.09	2.73/-0.09	3.02/-0.09	2.40/-0.41	ns	
		XC7K480T	2.47/-0.09	2.73/-0.09	3.02/-0.09	2.40/-0.41	ns	

### Notes:

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 47: Clock-Capable Clock Input Setup and Hold With PLL

Symbol	Description	Device	Speed Grade				Units
			1.0V		0.9V		
			-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to Clock-Capable Clock Input Signal for SSTL15 Standard. <sup>(1)</sup>							
$T_{PSPLLCC}/T_{PHPLLCC}$	No Delay clock-capable clock input and IFF <sup>(2)</sup> with PLL	XC7K70T	2.75/-0.32	3.04/-0.32	3.33/-0.32	2.42/-0.54	ns
		XC7K160T	2.85/-0.31	3.16/-0.31	3.46/-0.31	2.59/-0.56	ns
		XC7K325T	2.91/-0.27	3.24/-0.27	3.54/-0.27	2.80/-0.56	ns
		XC7K355T	2.79/-0.27	3.12/-0.27	3.40/-0.27	2.67/-0.52	ns
		XC7K410T	2.91/-0.27	3.24/-0.27	3.53/-0.27	2.78/-0.56	ns
		XC7K420T	2.83/-0.20	3.12/-0.20	3.41/-0.20	2.61/-0.50	ns
		XC7K480T	2.83/-0.20	3.12/-0.20	3.41/-0.20	2.61/-0.50	ns

**Notes:**

1. Setup and Hold times are measured over worst case conditions (process, voltage, temperature). Setup time is measured relative to the Global Clock input signal using the slowest process, highest temperature, and lowest voltage. Hold time is measured relative to the Global Clock input signal using the fastest process, lowest temperature, and highest voltage.
2. IFF = Input Flip-Flop or Latch
3. Use IBIS to determine any duty-cycle distortion incurred using various standards.

Table 48: Data Input Setup and Hold Times Relative to a Forwarded Clock Input Pin Using BUFIN

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
Input Setup and Hold Time Relative to a Forwarded Clock Input Pin Using BUFIN for SSTL15 Standard.						
$T_{PSCS}/T_{PHCS}$	Setup/Hold of I/O clock for HR I/O banks	-0.36/1.36	-0.36/1.50	-0.36/1.70	-0.44/1.87	ns
	Setup/Hold of I/O clock for HP I/O banks	-0.34/1.39	-0.34/1.53	-0.34/1.73	-0.44/1.87	ns

Table 49: Sample Window

Symbol	Description	Speed Grade				Units
		1.0V		0.9V		
		-3	-2/-2L	-1	-2L	
$T_{SAMP}$	Sampling Error at Receiver Pins <sup>(1)</sup>	0.51	0.56	0.61	0.56	ns
$T_{SAMP\_BUFIN}$	Sampling Error at Receiver Pins using BUFIN <sup>(2)</sup>	0.30	0.35	0.40	0.35	ns

**Notes:**

1. This parameter indicates the total sampling error of the Kintex-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the MMCM to capture the DDR input registers' edges of operation. These measurements include:
  - CLK0 MMCM jitter
  - MMCM accuracy (phase offset)
  - MMCM phase shift resolution
These measurements do not include package or clock tree skew.
2. This parameter indicates the total sampling error of the Kintex-7 FPGAs DDR input registers, measured across voltage, temperature, and process. The characterization methodology uses the BUFIN clock network and IDELAY to capture the DDR input registers' edges of operation. These measurements do not include package or clock tree skew.

## Additional Package Parameter Guidelines

The parameters in this section provide the necessary values for calculating timing budgets for Kintex-7 FPGA clock transmitter and receiver data-valid windows.

*Table 50: Package Skew*

Symbol	Description	Device	Package	Value	Units
$T_{PKGSKEW}$	Package Skew <sup>(1)</sup>	XC7K70T	FBG484	108	ps
			FBG676	135	ps
		XC7K160T	FBG484	118	ps
			FBG676	136	ps
			FFG676	161	ps
		XC7K325T	FBG676	146	ps
			FFG676	154	ps
			FBG900	163	ps
			FFG900	161	ps
		XC7K355T	FFG901	149	ps
		XC7K410T	FBG676	165	ps
			FFG676	168	ps
			FBG900	151	ps
			FFG900	146	ps
		XC7K420T	FFG901	149	ps
			FFG1156	145	ps
		XC7K480T	FFG901	149	ps
			FFG1156	145	ps

**Notes:**

1. These values represent the worst-case skew between any two SelectIO resources in the package: shortest delay to longest delay from die pad to ball.
2. Package delay information is available for these device/package combinations. This information can be used to deskew the package.

**Table 52** summarizes the DC specifications of the clock input of the GTX transceiver. Consult [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#) for further details.

**Table 52: GTX Transceiver Clock DC Input Level Specification**

Symbol	DC Parameter	Min	Typ	Max	Units
V <sub>IDIFF</sub>	Differential peak-to-peak input voltage	250	—	2000	mV
R <sub>IN</sub>	Differential input resistance	—	100	—	Ω
C <sub>EXT</sub>	Required external AC coupling capacitor	—	100	—	nF

## GTX Transceiver Switching Characteristics

Consult [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#) for further information.

**Table 53: GTX Transceiver Performance**

Symbol	Description	Output Divider	Speed Grade								Units	
			1.0V				0.9V					
			-3		-2/-2L		-1 <sup>(1)</sup>		-2L <sup>(2)</sup>			
			Package Type									
			FF	FB	FF	FB	FF	FB	FF	FB		
F <sub>GTXMAX</sub> <sup>(3)</sup>	Maximum GTX transceiver data rate		12.5	6.6	10.3125	6.6	8.0	6.6	6.6	6.6	Gb/s	
F <sub>GTXMIN</sub> <sup>(3)</sup>	Minimum GTX transceiver data rate		0.500	0.500	0.500	0.500	0.500	0.500	0.500	0.500	Gb/s	
F <sub>GTXCRANGE</sub>	CPLL line rate range	1	3.2–6.6								Gb/s	
		2	1.6–3.3								Gb/s	
		4	0.8–1.65								Gb/s	
		8	0.5–0.825								Gb/s	
		16	N/A								Gb/s	
F <sub>GTXQRANGE1</sub>	QPLL line rate range 1	1	5.93–8.0	5.93–6.6	5.93–8.0	5.93–6.6	5.93–8.0	5.93–6.6	5.93–6.6		Gb/s	
		2	2.965–4.0		2.965–4.0		2.965–4.0		2.965–3.3		Gb/s	
		4	1.4825–2.0		1.4825–2.0		1.4825–2.0		1.4825–1.65		Gb/s	
		8	0.74125–1.0		0.74125–1.0		0.74125–1.0		0.74125–0.825		Gb/s	
		16	N/A		N/A		N/A		N/A		Gb/s	
F <sub>GTXQRANGE2</sub>	QPLL line rate range 2 <sup>(4)</sup>	1	9.8–12.5	N/A	9.8–10.3125	N/A	N/A		N/A		Gb/s	
		2	4.9–6.25		4.9–5.15625		N/A		N/A		Gb/s	
		4	2.45–3.125		2.45–2.578125		N/A		N/A		Gb/s	
		8	1.225–1.5625		1.225–1.2890625		N/A		N/A		Gb/s	
		16	0.6125–0.78125		0.6125–0.64453125		N/A		N/A		Gb/s	
F <sub>GCPLLRANGE</sub>	GTX transceiver CPLL frequency range		1.6–3.3		1.6–3.3		1.6–3.3		1.6–3.3		GHz	
F <sub>GQPLLRANGE1</sub>	GTX transceiver QPLL frequency range 1		5.93–8.0		5.93–8.0		5.93–8.0		5.93–6.6		GHz	

Table 56: GTX Transceiver PLL /Lock Time Adaptation

Symbol	Description	Conditions	All Speed Grades			Units
			Min	Typ	Max	
T <sub>LOCK</sub>	Initial PLL lock		—	—	1	ms
T <sub>DLOCK</sub>	Clock recovery phase acquisition and adaptation time for decision feedback equalizer (DFE).	After the PLL is locked to the reference clock, this is the time it takes to lock the clock data recovery (CDR) to the data present at the input.	—	50,000	37 x10 <sup>6</sup>	UI
	Clock recovery phase acquisition and adaptation time for low-power mode (LPM) when the DFE is disabled.		—	50,000	2.3 x10 <sup>6</sup>	UI

Table 57: GTX Transceiver User Clock Switching Characteristics<sup>(1)(2)</sup>

Symbol	Description	Conditions	Speed Grade				Units	
			1.0V		0.9V			
			-3 <sup>(3)</sup>	-2/-2L <sup>(3)</sup>	-1 <sup>(4)</sup>	-2L <sup>(5)</sup>		
F <sub>TXOUT</sub>	TXOUTCLK maximum frequency		412.54	412.54	312.50	237.53	MHz	
F <sub>RXOUT</sub>	RXOUTCLK maximum frequency		412.54	412.54	312.50	237.53	MHz	
F <sub>TXIN</sub>	TXUSRCLK maximum frequency	16-bit data path	412.54	412.54	312.50	237.53	MHz	
		32-bit data path	391.08	322.37	250.00	206.27	MHz	
F <sub>RXIN</sub>	RXUSRCLK maximum frequency	16-bit data path	412.54	412.54	312.50	237.53	MHz	
		32-bit data path	391.08	322.37	250.00	206.27	MHz	
F <sub>TXIN2</sub>	TXUSRCLK2 maximum frequency	16-bit data path	412.54	412.54	312.50	237.53	MHz	
		32-bit data path	391.08	322.37	250.00	206.27	MHz	
		64-bit data path	195.54	161.19	125.00	103.14	MHz	
F <sub>RXIN2</sub>	RXUSRCLK2 maximum frequency	16-bit data path	412.54	412.54	312.50	237.53	MHz	
		32-bit data path	391.08	322.37	250.00	206.27	MHz	
		64-bit data path	195.54	161.19	125.00	103.14	MHz	

**Notes:**

1. Clocking must be implemented as described in [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#).
2. These frequencies are not supported for all possible transceiver configurations.
3. For speed grades -3, -2, -2L (1.0V), a 16-bit data path can only be used for speeds less than 6.6 Gb/s.
4. For speed grade -1, a 16-bit data path can only be used for speeds less than 5.0 Gb/s.
5. For speed grade -2L (0.9V), a 16-bit data path can only be used for speeds less than 3.8 Gb/s.

Table 58: GTX Transceiver Transmitter Switching Characteristics

Symbol	Description	Condition	Min	Typ	Max	Units
F <sub>GTXTX</sub>	Serial data rate range		0.500	—	F <sub>GTXMAX</sub>	Gb/s
T <sub>RTX</sub>	TX Rise time	20%–80%	—	40	—	ps
T <sub>FTX</sub>	TX Fall time	80%–20%	—	40	—	ps
T <sub>LLSKEW</sub>	TX lane-to-lane skew <sup>(1)</sup>		—	—	500	ps
V <sub>TXOOBVDP</sub>	Electrical idle amplitude		—	—	15	mV
T <sub>TXOOBTTRANSITION</sub>	Electrical idle transition time		—	—	140	ns
TJ <sub>12.5</sub>	Total Jitter <sup>(2)(4)</sup>	12.5 Gb/s	—	—	0.28	UI
DJ <sub>12.5</sub>	Deterministic Jitter <sup>(2)(4)</sup>		—	—	0.17	UI
TJ <sub>11.18</sub>	Total Jitter <sup>(2)(4)</sup>	11.18 Gb/s	—	—	0.28	UI
DJ <sub>11.18</sub>	Deterministic Jitter <sup>(2)(4)</sup>		—	—	0.17	UI

## GTX Transceiver Protocol Jitter Characteristics

For Table 60 through Table 65, the [UG476: 7 Series FPGAs GTX/GTH Transceiver User Guide](#) contains recommended settings for optimal usage of protocol specific characteristics.

**Table 60: Gigabit Ethernet Protocol Characteristics**

Description	Line Rate (Mb/s)	Min	Max	Units
<b>Gigabit Ethernet Transmitter Jitter Generation</b>				
Total transmitter jitter (T_TJ)	1250	–	0.24	UI
<b>Gigabit Ethernet Receiver High Frequency Jitter Tolerance</b>				
Total receiver jitter tolerance	1250	0.749	–	UI

**Table 61: XAUI Protocol Characteristics**

Description	Line Rate (Mb/s)	Min	Max	Units
<b>XAUI Transmitter Jitter Generation</b>				
Total transmitter jitter (T_TJ)	3125	–	0.35	UI
<b>XAUI Receiver High Frequency Jitter Tolerance</b>				
Total receiver jitter tolerance	3125	0.65	–	UI

**Table 62: PCI Express Protocol Characteristics<sup>(1)</sup>**

Standard	Description	Line Rate (Mb/s)	Min	Max	Units
<b>PCI Express Transmitter Jitter Generation</b>					
PCI Express Gen 1	Total transmitter jitter	2500	–	0.25	UI
PCI Express Gen 2	Total transmitter jitter	5000	–	0.25	UI
PCI Express Gen 3 <sup>(2)</sup>	Total transmitter jitter uncorrelated	8000	–	31.25	ps
	Deterministic transmitter jitter uncorrelated		–	12	ps
<b>PCI Express Receiver High Frequency Jitter Tolerance</b>					
PCI Express Gen 1	Total receiver jitter tolerance	2500	0.65	–	UI
PCI Express Gen 2 <sup>(3)</sup>	Receiver inherent timing error	5000	0.40	–	UI
	Receiver inherent deterministic timing error		0.30	–	UI
PCI Express Gen 3 <sup>(2)</sup>	Receiver sinusoidal jitter tolerance	0.03 MHz–1.0 MHz	1.00	–	UI
		1.0 MHz–10 MHz	Note 4		UI
		10 MHz–100 MHz	0.10	–	UI

### Notes:

1. Tested per card electromechanical (CEM) methodology.
2. PCI-SIG 3.0 certification and compliance test boards are currently not available.
3. Using common REFCLK.
4. Between 1 MHz and 10 MHz the minimum sinusoidal jitter roll-off with a slope of 20dB/decade.

**Table 65: CPRI Protocol Characteristics**

Description	Line Rate (Mb/s)	Min	Max	Units
<b>CPRI Transmitter Jitter Generation</b>				
Total transmitter jitter	614.4	–	0.35	UI
	1228.8	–	0.35	UI
	2457.6	–	0.35	UI
	3072.0	–	0.35	UI
	4915.2	–	0.3	UI
	6144.0	–	0.3	UI
	9830.4	–	Note 1	UI
<b>CPRI Receiver Frequency Jitter Tolerance</b>				
Total receiver jitter tolerance	614.4	0.65	–	UI
	1228.8	0.65	–	UI
	2457.6	0.65	–	UI
	3072.0	0.65	–	UI
	4915.2	0.95	–	UI
	6144.0	0.95	–	UI
	9830.4	Note 1	–	UI

**Notes:**

- Tested per SFP+ specification, see [Table 64](#).

**Integrated Interface Block for PCI Express Designs Switching Characteristics**

More information and documentation on solutions for PCI Express designs can be found at:

<http://www.xilinx.com/technology/protocols/pciexpress.htm>

**Table 66: Maximum Performance for PCI Express Designs**

Symbol	Description	Speed Grade				Units
		1.0V			0.9V	
		-3	-2/-2L	-1	-2L	
FPIPECLK	Pipe clock maximum frequency	250.00	250.00	250.00	250.00	MHz
FUSERCLK	User clock maximum frequency	500.00	500.00	250.00	250.00	MHz
FUSERCLK2	User clock 2 maximum frequency	250.00	250.00	250.00	250.00	MHz
FRPCLK	DRP clock maximum frequency	250.00	250.00	250.00	250.00	MHz